INTEGRATED CIRCUITS

DATA SHEET

74LV03Quad 2-input NAND gate

Product data Supersedes data of 1998 Apr 20





Quad 2-input NAND gate

74LV03

FEATURES

- Wide operating voltage: 1.0 V to 5.5 V
- Optimized for Low Voltage applications: 1.0 V to 3.6 V
- Accepts TTL input levels between V_{CC} = 2.7 V and V_{CC} = 3.6 V
- Typical V_{OLP} (output ground bounce) < 0.8 V @ V_{CC} = 3.3 V, T_{amb} = 25 °C
- Typical V_{OHV} (output V_{OH} undershoot) > 2 V @ V_{CC} = 3.3 V, T_{amb} = 25 °C
- Level shifter capability
- Output capability: standard (open drain)
- I_{CC} category: SSI

DESCRIPTION

The 74LV03 is a low-voltage Si-gate CMOS device and is pin and function compatible with 74HC/HCT03.

The 74LV03 provides the 2-input NAND function.

The 74LV03 has open-drain N-transistor outputs, which are not clamped by a diode connected to $V_{\mbox{\footnotesize{CC}}}.$ In the OFF-state, i.e., when one input is LOW, the output may be pulled to any voltage between GND and V_{Omax}. This allows the device to be used as a LOW-to-HIGH or HIGH-to-LOW level shifter. For digital operation and OR-tied output applications, these devices must have a pull-up resistor to establish a logic HIGH level.

QUICK REFERENCE DATA

GND = 0 V; $T_{amb} = 25 \, ^{\circ}C$; $t_r = t_f \le 2.5 \, \text{ns}$

SYMBOL	PARAMETER	CONDITIONS	TYPICAL	UNIT
t _{PZL} /t _{PLZ}	Propagation delay nA, nB to nY	$C_L = 15 \text{ pF}$ $V_{CC} = 3.3 \text{ V}$	8	ns
C _I	Input capacitance		3.5	pF
C _{PD}	Power dissipation capacitance per gate	Notes 1, 2	4	pF

NOTES:

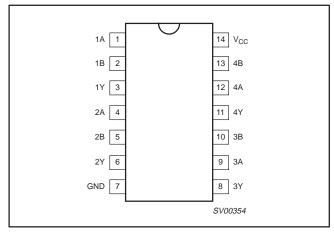
- C_{PD} is used to determine the dynamic power dissipation (P_D in μW)
 - $$\begin{split} &P_D = C_{PD} \times V_{CC}{}^2 \times f_i \times N + \Sigma \left(C_L \times V_{CC}{}^2 \times f_o \right) \quad \text{where:} \\ &N = \text{the number of outputs switching;} \end{split}$$

 - f_i = input frequency in MHz; C_L = output load capacitance in pF; f_o = output frequency in MHz; V_{CC} = supply voltage in V;
- $\begin{array}{l} \Gamma_0 = \text{output inequality in Nin 12, V}_{CC} = \text{supply voltage in V}, \\ \Sigma \left(C_L \times V_{CC}^2 \times f_0 \right) = \text{sum of the outputs.} \\ \text{The condition is V}_I = \text{GND to V}_{CC} \\ \text{The given value of C}_{PD} \text{ is obtained with : } C_L = 0 \text{ pF and } R_L = \infty \end{array}$

ORDERING INFORMATION

PACKAGES		TEMPERATURE RANGE	ORDER CODE	PKG. DWG. #	
14-Pin Plastic	SO	-40 °C to +125 °C	74LV03D	SOT108-1	

PIN CONFIGURATION



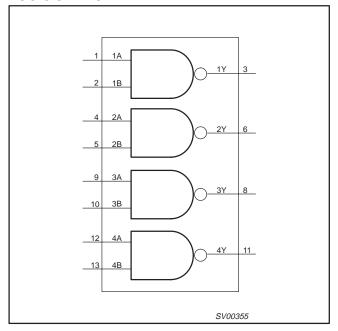
PIN DESCRIPTION

PIN NUMBER SYMBOL 1, 4, 9, 12 1A to 4A		FUNCTION			
		Data inputs			
2, 5, 10, 13	1B to 4B	Data inputs			
3, 6, 8, 11	1Y to 4Y	Data outputs			
7	GND	Ground (0 V)			
14	V _{CC}	Positive supply voltage			

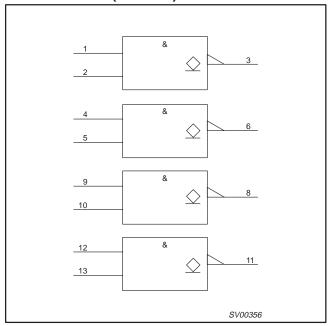
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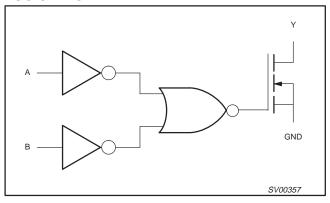
LOGIC SYMBOL



LOGIC SYMBOL (IEEE/IEC)



LOGIC DIAGRAM



FUNCTION TABLE

INP	OUTPUT		
nA	nB	nY	
L	L	Z	
L	Н	Z	
Н	L	Z	
Н	Н	L	

NOTES:
H = HIGH voltage level
L = LOW voltage level
Z = High impedance OFF-state

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RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER CONDITIONS			TYP.	MAX	UNIT
V _{CC}	DC supply voltage	See Note1	1.0	3.3	5.5	V
VI	Input voltage		0	_	V _{CC}	V
V _O	Output voltage		0	ı	V _{CC}	V
T _{amb}	Operating ambient temperature range in free air	See DC and AC characteristics	-40 -40		+85 +125	°C
		V _{CC} = 1.0 V to 2.0 V	_	_	500	ns/V
	Input rise and fall times	V _{CC} = 2.0 V to 2.7 V	_	-	200	
t _r , t _f		V _{CC} = 2.7 V to 3.6 V	_	_	100	
		$V_{CC} = 3.6 \text{ V to } 5.5 \text{ V}$	_	-	50	

NOTES:

ABSOLUTE MAXIMUM RATINGS^{1, 2}

In accordance with the Absolute Maximum Rating System (IEC 134). Voltages are referenced to GND (ground = 0 V).

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V _{CC}	DC supply voltage		-0.5 to +7.0	V
±I _{IK}	DC input diode current	$V_{I} < -0.5 \text{ or } V_{I} > V_{CC} + 0.5 \text{ V}$	20	mA
±I _{OK}	DC output diode current	$V_{O} < -0.5 \text{ or } V_{O} > V_{CC} + 0.5 \text{ V}$	50	mA
±IO	DC output source or sink current – standard outputs	$-0.5V < V_O < V_{CC} + 0.5 V$	25	mA
±I _{GND} , ±I _{CC}	DC V _{CC} or GND current for types with –standard outputs		50	mA
T _{stg}	Storage temperature range		-65 to +150	°C
P _{TOT}	Power dissipation per package –plastic mini-pack (SO)	for temperature range: -40 °C to +125 °C above +70 °C derate linearly with 8 mW/K	500	mW

NOTES:

¹ The LV is guaranteed to function down to V_{CC} = 1.0 V (input levels GND or V_{CC}); DC characteristics are guaranteed from V_{CC} = 1.2 V to V_{CC} = 5.5 V.

¹ Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

² The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

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DC CHARACTERISTICS

Over recommended operating conditions voltages are referenced to GND (ground = 0 V)

				LIMITS					
SYMBOL	PARAMETER	PARAMETER TEST CONDITIONS		-40°C to +85°C -40°C to				UNIT	
			MIN	TYP ¹	MAX	MIN	MAX	1	
		V _{CC} = 1.2 V	0.9			0.9			
\/	HIGH level Input	V _{CC} = 2.0 V	1.4			1.4		1 ,,	
V_{IH}	voltage	V _{CC} = 2.7 V to 3.6 V	2.0			2.0		-	
		V _{CC} = 4.5 V to 5.5 V	0.7*V _{CC}			0.7*V _{CC}		1	
		V _{CC} = 1.2 V			0.3		0.3		
$V_{\rm IL}$	LOW level Input	V _{CC} = 2.0 V			0.6		0.6]	
VIL	voltage	V _{CC} = 2.7 V to 3.6 V			0.8		0.8	1 '	
		V _{CC} = 4.5 V to 5.5 V			0.3*V _{CC}		0.3*V _{CC}	1	
		$V_{CC} = 1.2 \text{ V}; V_I = V_{IH} \text{ or } V_{IL;} -I_O = 100 \mu\text{A}$		1.2					
		$V_{CC} = 2.0 \text{ V}; V_I = V_{IH} \text{ or } V_{IL;} -I_O = 100 \mu\text{A}$	1.8	2.0		1.8		1	
V_{OH}	HIGH level output voltage; all outputs	$V_{CC} = 2.7 \text{ V}; V_I = V_{IH} \text{ or } V_{IL}; -I_O = 100 \mu\text{A}$	2.5	2.7		2.5		V	
	Voltago, all outputs	$V_{CC} = 3.0 \text{ V}; V_I = V_{IH} \text{ or } V_{IL;} -I_O = 100 \mu\text{A}$	2.8	3.0		2.8		1	
		$V_{CC} = 4.5 \text{ V}; V_I = V_{IH} \text{ or } V_{IL;} -I_O = 100 \mu\text{A}$	4.3	4.5		4.3		1	
V _{OH}	HIGH level output voltage;	$V_{CC} = 3.0 \text{ V}; V_I = V_{IH} \text{ or } V_{IL;} -I_O = 6 \text{ mA}$	2.40	2.82		2.20		V	
VОН	STANDARD outputs	$V_{CC} = 4.5 \text{ V;} V_{I} = V_{IH} \text{ or } V_{IL;} -I_{O} = 12 \text{ mA}$	3.60	4.20		3.50			
	LOW level output voltage; all outputs	$V_{CC} = 1.2 \text{ V}; V_I = V_{IH} \text{ or } V_{IL}; I_O = 100 \mu\text{A}$		0					
		V_{CC} = 2.0 V; V_I = V_{IH} or V_{IL} ; I_O = 100 μA		0	0.2		0.2		
V_{OL}		V_{CC} = 2.7 V; V_I = V_{IH} or V_{IL} ; I_O = 100 μ A		0	0.2		0.2	V	
		$V_{CC} = 3.0 \text{ V}; V_I = V_{IH} \text{ or } V_{IL}; I_O = 100 \mu\text{A}$		0	0.2		0.2		
		V_{CC} = 4.5 V; V_I = V_{IH} or V_{IL} ; I_O = 100 μA		0	0.2		0.2		
V _{OL}	LOW level output voltage;	$V_{CC} = 3.0 \text{ V}; V_I = V_{IH} \text{ or } V_{IL}; I_O = 6 \text{ mA}$		0.25	0.40		0.50		
VOL	STANDARD outputs	$V_{CC} = 4.5 \text{ V}; V_I = V_{IH} \text{ or } V_{IL}; I_O = 12 \text{ mA}$		0.35	0.55		0.65] `	
I _{OZ}	HIGH level output leakage current	$V_{CC} = 2.0 \text{ V to } 3.6 \text{ V; } V_I = V_{IL;}$ $V_O = V_{CC} \text{ or GND}$			5.0		10	μА	
I _{OZ}	HIGH level output leakage current	$V_{CC} = 2.0 \text{ V to } 3.6 \text{ V; } V_I = V_{IL;}$ $V_O = 6.0 \text{ V}^2$			10		20	μА	
IĮ	Input leakage current	$V_{CC} = 5.5 \text{ V}; V_I = V_{CC} \text{ or GND}$			1.0		1.0	μА	
I _{CC}	Quiescent supply current; SSI	$V_{CC} = 5.5 \text{ V}; V_{I} = V_{CC} \text{ or GND}; I_{O} = 0$			20.0		40	μА	
Δl _{CC}	Additional quiescent supply current per input	$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V; } V_{I} = V_{CC} - 0.6 \text{ V}$			500		850	μА	

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NOTES:

¹ All typical values are measured at T_{amb} = 25 °C. 2 The maximum operating output voltage (V_{O(max)}) is 6.0 V.

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AC CHARACTERISTICS FOR 74LV03

GND = 0 V; t_r = t_f \leq 2.5 ns; C_L = 50 pF; R_L = 1 $k\Omega$

SYMBOL	PARAMETER	WAVEFORM	CONDITION	_,	LIMITS 40 to +85 °	С	LIM -40 to -	ITS ⊦125 °C	UNIT
			V _{CC} (V) MIN TYP ¹	MAX	MIN	MAX			
	Propagation delay nA, nB, to nY	Propagation delay A. nB. to nY	1.2	_	50	_	_	_	
			2.0	_	17	26	_	31	
t _{PZL} /t _{PLZ}			2.7	-	13	19	-	23	ns
		,,	3.0 to 3.6	_	10 ²	16	_	19	
			4.5 to 5.5	_	_3	13	_	16	

NOTE:

- 1 Unless otherwise stated, all typical values are at T_{amb} = 25 °C.
- 2 Typical value measured at $V_{CC} = 3.3 \text{ V}$.
- 3 Typical value measured at $V_{CC} = 5.0 \text{ V}$.

AC WAVEFORMS

 $V_M = 1.5 \text{ V at } V_{CC} \ge 2.7 \text{ V} \le 3.6 \text{ V}$

 $V_M = 0.5 \text{ V} * V_{CC} \text{ at } V_{CC} < 2.7 \text{ V} \text{ and } \ge 4.5 \text{ V}$

 $V_{\mbox{\scriptsize OL}}$ and $V_{\mbox{\scriptsize OH}}$ are the typical output voltage drop that occur with the

 $V_X = V_{OL} + 0.3 \text{ V}$ at $V_{CC} \ge 2.7 \text{ V}$ and $\le 3.6 \text{ V}$

 $V_X = V_{OL} + 0.1 * V_{CC}$ at $V_{CC} < 2.7 \text{ V}$ and $\geq 4.5 \text{ V}$

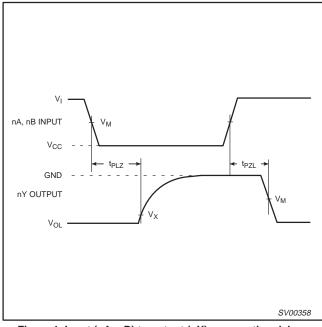


Figure 1. Input (nA, nB) to output (nY) propagation delays.

TEST CIRCUIT

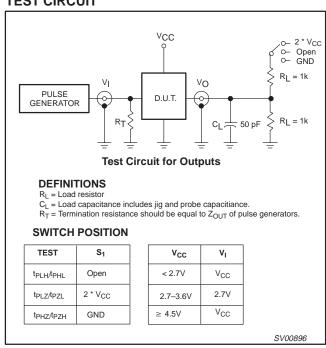


Figure 2. Load circuitry for switching times

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REVISION HISTORY

Rev	Date	Description
_3	20030303	Product data (9397 750 11191). ECN 853-1963 29494 of 07 February 2003. Supersedes data of 1998 Apr 20 (9397 750 04403).
		Modifications:
		Delete DIL, SSOP and TSSOP package ordering and package outlines (discontinued options).
		Correct power dissipation formula.
_2	19980420	Product specification (9397 750 04403). ECN 853-1963 19257 of 20 April 1998. Supersedes data of 1997 Mar 28.

Data sheet status

Level	Data sheet status [1]	Product status ^{[2] [3]}	Definitions
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Phillips Semiconductors reserves the right to change the specification in any manner without notice.
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^[1] Please consult the most recently issued data sheet before initiating or completing a design.

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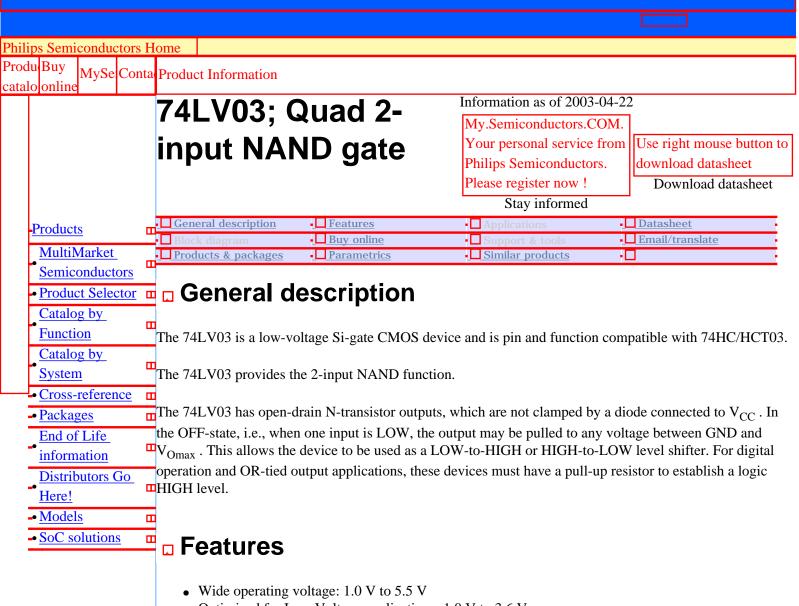
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^[2] The product status of the device(s) described in this data sheet may have changed since this data sheet was published. The latest information is available on the Internet at URL http://www.semiconductors.philips.com.

^[3] For data sheets describing multiple type numbers, the highest-level product status determines the data sheet status.



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- Level shifter capability
- Output capability: standard (open drain)
- I_{CC} category: SSI

Datasheet

Type number	<u>Title</u>	Publication release date	<u>Datasheet status</u>	Page count	File size (kB)	Datasheet
74LV03	Quad 2- input NAND gate	3/3/2003	Product specification	7	58	<u>Download</u>

Parametrics

Type number	Package	Description	Propagation Delay(ns)	Voltage	of	Power Dissipation Considerations	Logic Switching Levels	Output Drive Capability
74LV03D	SOT108- 1 (SO14)	Quad 2- Input NAND Gate with Level Shift Capability	15	Low	14	Low Power or Battery Applications	TTL	Low

□ Products, packages, availability and ordering

Type number	North American type number	Ordering code (12NC)	Marking/Packing IC packing info	Package	Device status	Buy online	
74LV03D	74LV03D	9351 758 20112	Standard Marking * Tube	SOT108-1 (SO14)	Full production	order this	1_
	74LV03D- T	9351 758 20118	Standard Marking * Reel Pack, SMD, 13"	SOT108-1 (SO14)	Full production	order this	

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